Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/712,169	DEHAAN ET AL.
Examiner	Art Unit
Tam M. Nguyen	1764

		<del></del>			
SEARCHED					
Class	Subclass	Date	Examiner		
208	58 62 108 15 18	9/29/2005	tn		
	-				
	-				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	l				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAST		10/30/2005	tn
			_